NSN 6625-01-259-8161

T228-a

Semiconductor Device Test Set - Page 1 of 1



View Online at https://aerobasegroup.com/nsn/6625-01-259-8161 Width: 425.5 millimeters Ac Voltage Rating: Between 100.0 volts and 240.0 volts Frequency Rating: Between 48.0 hertz and 66.0 hertz Depth: 574.0 millimeters **Electrical Power Source Relationship:** Operating Inclosure Feature: Single item w/housing **Test Type For Which Designed:** Rf impedance; semiconductor measurement Phase: Two **Special Features:** Opr temp 0 - 55 degrees c; type of tests: izi-theda, iyi-theda, iri-theda r-x, g-b, ix-iy, l-r x g x d x q c-r x g x d x q; -40 to +40 vdc bias internal and external; +.1 amps dc maximum for dc bias; internal, external, or manual trigger **Functional Description:** Performs analysis of 14 parameters with 4.5 digit resolution across a 1 to 1000 mhz freq range Height: 230.0 millimeters **Surface Treatment:** Any acceptable Shelf Life: N/a **Unit Of Measure: Demilitarization:** Yes - demil/mli Fiig: